

S/N 09/834,751

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:	Sergey A. Velichko et al.	Examiner:	Craig Steven Miller
Serial No.:	09/834,751	Group Art Unit:	2857
Filed:	April 13, 2001	Docket:	303.750US1
Title:	CONCURRENT CONTROL OF SEMICONDUCTOR PARAMETRIC TESTING		

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

MS Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

In compliance with the duty imposed by 37 C.F.R. § 1.56, and in accordance with 37 C.F.R. §§ 1.97 *et. seq.*, the enclosed materials are brought to the attention of the Examiner for consideration in connection with the above-identified patent application. Applicants respectfully request that this Supplemental Information Disclosure Statement be entered and the documents listed on the attached Form 1449 be considered by the Examiner and made of record. Pursuant to the provisions of MPEP 609, Applicants request that a copy of the 1449 form, initialed as being considered by the Examiner, be returned to the Applicants with the next official communication.

Pursuant to 37 C.F.R. §1.97(c)(2), please charge the required the fee of \$180.00 as set forth in 37 C.F.R. §1.17(p) to Deposit Account No. 19-0743.

Pursuant to 37 C.F.R. 1.98(a)(2), Applicant believes that copies of cited U.S. Patents and Published Applications are no longer required to be provided to the Office. Notification of this change was provided in the United States Patent and Trademark Office OG Notices dated October 12, 2004. Thus, Applicant has not included copies of any US Patents or Published Applications cited with this submission. Should the Office require copies to be provided, Applicant respectfully requests that notice of such requirement be directed to Applicant's below-signed representative. Applicant acknowledges the requirement to submit copies of foreign patent documents and non-patent literature in accordance with 37 C.F.R. 1.98(a)(2).

The Examiner is invited to contact the Applicants' Representative at the below-listed telephone number if there are any questions regarding this communication.

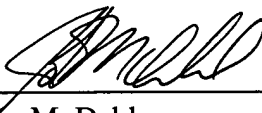
Respectfully submitted,

SERGEY A. VELICHKO ET AL.

By their Representatives,


SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A.
P.O. Box 2938
Minneapolis, MN 55402
(612) 349-9581

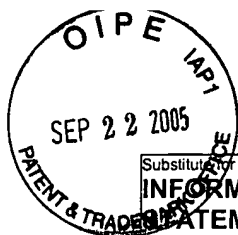
Date Sep 19 05

By 
John M. Dahl
Reg. No. 44,639

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: MS Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 19 day of September, 2005.

Tim Kohut
Name


Signature



Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Complete if Known

Application Number	09/834,751
Filing Date	April 13, 2001
First Named Inventor	Velichko, Sergey
Group Art Unit	2857
Examiner Name	Miller, Craig

Sheet 1 of 1

Attorney Docket No: 303.750US1

US PATENT DOCUMENTS

Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Filing Date If Appropriate
	US-2005/0021273 A1	01/27/2005	Dorough, M. J., et al.	08/24/2004
	US-6,549,863	04/15/2003	Morinaga, K.	08/21/2000
	US-6,563,331	05/13/2003	Maeng, J. S.	08/21/2001
	US-6,859,760	02/22/2005	Dorough, M. J.	05/20/2003

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Foreign Document No	Publication Date	Name of Patentee or Applicant of cited Document	T ²
--------------------	---------------------	------------------	-------------------------------------------------	----------------

OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		CHEUNG, D. , et al., "The INMOS Integrated Parametric Test and Analysis System", <u>Proceedings IEEE 1989 International Conference on Microelectronic Test Structures</u> , vol. 2(1), (Mar., 13-14, 1989),45-50	
		GRANIERI, M. N., "System Engineering Considerations and Methodology for Effecting a Cohesive Functional/Parametric Testing Strategy", <u>IEEE Automatic Testing Conference</u> , (Sep., 25-28, 1989),1-8	
		HAMILTON, A. , et al., "An Expert System for Process Diagnosis [MOS Product Testing]", <u>Proceedings IEEE 1989 International Conference on Microelectronic Test Structures</u> , vol. 2(1), (Mar., 13-14, 1989),55-57	
		MADGE, R. , et al., "In Search of the Optimum Test Set - Adaptive Test Methods For Maximum Defect Coverage and Lowest Test Cost", <u>IEEE International Test Conference</u> , (Oct., 26-28, 2004),	
		PEREZ, R. A., et al., "Integrating Expert Systems With A Relational Database In Semiconductor Manufacturing", <u>IEEE Transactions on Semiconductor Manufacturing</u> , vol. 6(3), (Aug., 03, 1993),199-206	
		WEBER, C , "Standardization of CMOS Unit Process Development", <u>Proceedings IEEE 1989 International Conference on Microelectronic Test Structures</u> , (Mar., 13-14, 1989),39-44	

EXAMINER

DATE CONSIDERED

Substitute Disclosure Statement Form (PTO-1449)

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹ Applicant's unique citation designation number (optional) ² Applicant is to place a check mark here if English language Translation is attached